Search Notes

Application/Control	No.

Applicant(s)/Patent under Reexamination

10/081,863 Examiner NEFF, C. ANDREW

Ellen C. Tran

2134

	SEARCHED				
Class	Subclass	Date	Examiner		
705	12	11/20/2005	ECT		
726	26	11/20/2005	ECT		
713	156	11/20/2005	ECT		
380	28	8/14/2006	ECT		
705	12	8/14/2006	ECT		
726	26	8/14/2006	ECT		
713	156	8/14/2006	ECT		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES, INVENTOR	11/20/2005	ECT
STIC SEARCH EIC 2100	11/20/2005	ECT
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	8/14/2006	ECT